

CMI563®

For surface copper measurement

Oxford Instruments' CMI563 product was designed specifically for copper foil on rigid, flexible, single and double-sided, or multi-layer PCB boards

The **CMI563** employs the micro resistance test method technology, providing the most effective and efficient way of achieving accurate, precise measurement of surface copper thickness, including copper-clad laminate, electroless, and electrolytic copper. Featuring the market's most advanced test technology, copper plating on the opposing side of the printed circuit board will not interfere with precise, reliable readings, regardless of laminate thickness.

The innovative **CMI563** gauge includes the SRP-4 Probe engineered with user replaceable probe tips. These tip replacements are more convenient and less expensive as compared to probe replacement. The **CMI563** is user selectable for electroless and electrodeposited copper types, and even fine line trace measurements, no user calibration required. NIST-traceable check standards are available in a variety of thicknesses. This quality instrument is backed by warranty and Oxford Instruments' world-class customer service.

SRP-4 Probe

The tethered SRP-4 probe features a rugged, reliable cable for field applications. Additionally, the SRP-4's small footprint is convenient and user-friendly.

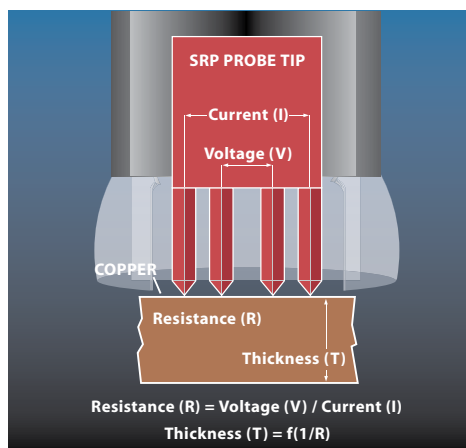


The Business of Science®

Micro resistance technology

The micro resistance test method technology uses four contact points to generate an electrical signal from the surface copper. The SRP-4 probe consists of four pins encased securely in a patented design which delivers high precision with a small footprint and minimal surface marking. The see-through material allows view of the pins for easy placement on small traces. The pins are a high-durability alloy to resist breakage and wear. When placed on the surface copper sample, a constant current is passed between the outer pins, and voltage drop is measured between the inner pins. Using Ohm's Law, voltage is converted to resistance and thickness is computed as a function of resistance. The micro resistance method

delivers highly accurate copper thickness measurement for copper plating applications



User replaceable probe tips (patent 7,148,712)

The SRP-4 features user-replaceable probe tips. A broken probe tip can be quickly and easily replaced on site, minimizing downtime. These



replacement probe tips are a far more economical alternative to replacing the entire probe. One replacement probe tip comes standard with the 563.

Additional probe tips are available in packages of three.

Specifications:

Accuracy: $\pm 1\%$ ($\pm 0.1 \mu\text{m}$) with reference to standards

Precision: Electroless Copper: 0.2 % standard deviation typical
Electrodeposited Copper: 0.5% standard deviation typical

Resolution: 0.01 mils > 1 mil, 0.001 mils < 1 mil, $0.1 \mu\text{m}$ > $10 \mu\text{m}$, $0.01 \mu\text{m}$ < $10 \mu\text{m}$, $0.001 \mu\text{m}$ < $1 \mu\text{m}$

Thickness Range:

Electroless Copper: 10 μin –500 μin ($0.25 \mu\text{m}$ – $12.7 \mu\text{m}$),

Electrodeposited Copper: 0.1 mil to 6 mil (152 μm),

Fine Line Measure: trace width 8 mil to 250 mil (203 μm –6350 μm)

Memory Capacity: 13,500 readings

Dimensions: 5 7/8" (L) x 3 1/8" (W) x 1 3/16" (D) (14.9 x 7.94 x 3.02 cm)

Weight: 9 oz (0.26 kg) including battery

Units: Automatic conversion between imperial and metric with a keystroke

Battery: 9V Alkaline

Battery Life: 65 continuous hours

Interface: RS-232 serial port output with adjustable baud rate, for a printer or PC download

Display: Four-digit LCD display, two-digit memory location, 1/2" (1.27cm) character height

Statistical Display: Number of readings, standard deviation, mean, high, low

Statistical Report (when interfaced with a serial printer or PC download): Memory location, number of readings, copper type, fine line trace width, date/time, mean, standard deviation, percent deviation, accuracy, high, low, range, cpk, individual readings, time-stamp, histogram

PC Download: Downloads all readings at a memory location with one keystroke

Oxford Instruments Industrial Analysis

For more information please email:
industrial@oxinst.com

North America

Scotts Valley, CA
Tel: +1 831 439 9729

UK

High Wycombe
Tel: +44 (0) 1494 442255

China

Shanghai
Tel: +86 21 6132 9688

Finland

Espoo
Tel: +358 9 329 411

Germany

Uedem
Tel: +49 (0) 2825 93 83 -0

Latin America

Concord MA
Tel: +1 978 369 9933 Ext. 220

Singapore

Tel: +65 6337 6848

visit www.oxford-instruments.com for more information

www.oxford-instruments.com

This publication is the copyright of Oxford Instruments plc and provides outline information only, which (unless agreed by the company in writing) may not be used, applied or reproduced for any purpose or form part of any order or contract or regarded as the representation relating to the products or services concerned. Oxford Instruments' policy is one of continued improvement. The company reserves the right to alter, without notice the specification, design or conditions of supply of any product or service. Oxford Instruments acknowledges all trademarks and registrations. © Oxford Instruments plc, 2010. All rights reserved. Part no: OIIA/079/A/0210



The Business of Science®